

ABSTRACT

The invention refers to a method which generates an IC tester control consisting of numerous test instructions for a plurality of specific test environments, which can generate and measure analog and digital signals for an IC, in particular a mixed-signal IC. The method obtains data and control instructions from multidimensional test matrices independent of the test environment, such as matrix-like databases or libraries. The data and control instructions independent of the test environment are converted by means of a code generator into a syntax which is dependent on the test environment and which can be integrated into a general syntax dependent on the test environment, so that the syntax dependent on the test environment and the general syntax dependent on the test environment together form a complete control, comprising analog and digital signals, for one of the specific test environments.